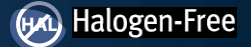




# THE DATASHEET OF EPC2015C



## EPC2015C – Enhancement Mode Power Transistor

 $V_{DS}$ , 40 V $R_{DS(on)}$ , 4 m $\Omega$  $I_D$ , 53 A

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low  $R_{DS(on)}$ , while its lateral device structure and majority carrier diode provide exceptionally low  $Q_G$  and zero  $Q_{RR}$ . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

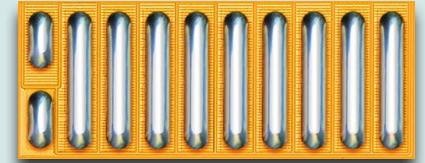
Maximum Ratings			
PARAMETER		VALUE	UNIT
$V_{DS}$	Drain-to-Source Voltage (Continuous)	40	V
	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	48	
$I_D$	Continuous ( $T_A = 25^\circ\text{C}$ , $R_{\theta JA} = 6^\circ\text{C/W}$ )	53	A
	Pulsed (25°C, $T_{PULSE} = 300 \mu\text{s}$ )	235	
$V_{GS}$	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
$T_J$	Operating Temperature	-40 to 150	°C
$T_{STG}$	Storage Temperature	-40 to 150	

Thermal Characteristics			
PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.8	°C/W
$R_{\theta JB}$	Thermal Resistance, Junction to Board	1.7	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1)	54	

Note 1:  $R_{\theta JA}$  is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See [http://epc-co.com/epc/documents/product-training/Appnote\\_Thermal\\_Performance\\_of\\_eGaN\\_FETs.pdf](http://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf) for details.

Static Characteristics ( $T_J = 25^\circ\text{C}$ unless otherwise stated)						
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$BV_{DSS}$	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V}$ , $I_D = 500 \mu\text{A}$	40			V
$I_{DSS}$	Drain-Source Leakage	$V_{GS} = 0 \text{ V}$ , $V_{DS} = 32 \text{ V}$		200	400	$\mu\text{A}$
$I_{GSS}$	Gate-to-Source Forward Leakage	$V_{GS} = 5 \text{ V}$		1	7	mA
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 \text{ V}$		200	400	$\mu\text{A}$
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 9 \text{ mA}$	0.8	1.4	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}$ , $I_D = 33 \text{ A}$		3.2	4	m $\Omega$
$V_{SD}$	Source-Drain Forward Voltage	$I_S = 0.5 \text{ A}$ , $V_{GS} = 0 \text{ V}$		1.7		V

All measurements were done with substrate connected to source.



EPC2015C eGaN® FETs are supplied only in passivated die form with solder bars  
Die size: 4.1 mm x 1.6 mm

**Applications**

- High Frequency DC-DC Conversion
- Point-of-Load Converters
- Industrial Automation
- Synchronous Rectification
- Class-D Audio
- Low Inductance Motor Drives

**Benefits**

- Ultra High Efficiency
- Ultra Low Switching and Conduction Losses
- Zero  $Q_{RR}$
- Ultra Small Footprint



Dynamic Characteristics ( $T_j = 25^\circ\text{C}$  unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$C_{ISS}$	Input Capacitance	$V_{DS} = 20\text{ V}, V_{GS} = 0\text{ V}$		980	1180	pF
$C_{RSS}$	Reverse Transfer Capacitance			18		
$C_{OSS}$	Output Capacitance			710	1070	
$C_{OSS(ER)}$	Effective Output Capacitance, Energy Related (Note 2)	$V_{DS} = 0\text{ to }20\text{ V}, V_{GS} = 0\text{ V}$		870		
$C_{OSS(TR)}$	Effective Output Capacitance, Time Related (Note 3)			940		
$R_G$	Gate Resistance			0.3		$\Omega$
$Q_G$	Total Gate Charge	$V_{DS} = 20\text{ V}, V_{GS} = 5\text{ V}, I_D = 33\text{ A}$		8.7	11.2	nC
$Q_{GS}$	Gate-to-Source Charge	$V_{DS} = 20\text{ V}, I_D = 33\text{ A}$		2.7		
$Q_{GD}$	Gate-to-Drain Charge			1.2		
$Q_{G(TH)}$	Gate Charge at Threshold			1.9		
$Q_{OSS}$	Output Charge	$V_{DS} = 20\text{ V}, V_{GS} = 0\text{ V}$		19	29	
$Q_{RR}$	Source-Drain Recovery Charge			0		

All measurements were done with substrate connected to source.

Note 2:  $C_{OSS(ER)}$  is a fixed capacitance that gives the same stored energy as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50%  $BV_{DSS}$ .

Note 3:  $C_{OSS(TR)}$  is a fixed capacitance that gives the same charging time as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50%  $BV_{DSS}$ .

Figure 1: Typical Output Characteristics at 25°C

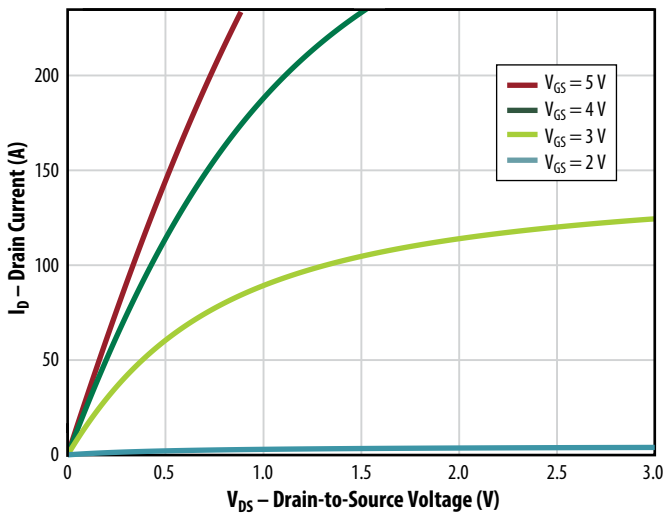


Figure 2: Transfer Characteristics

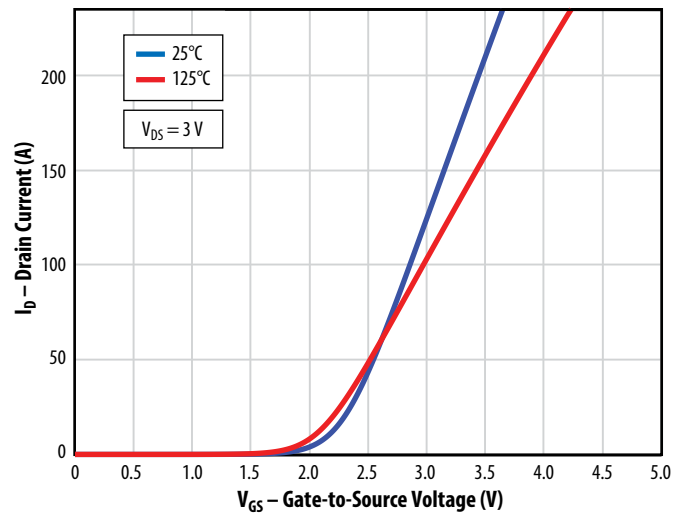


Figure 3:  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Drain Currents

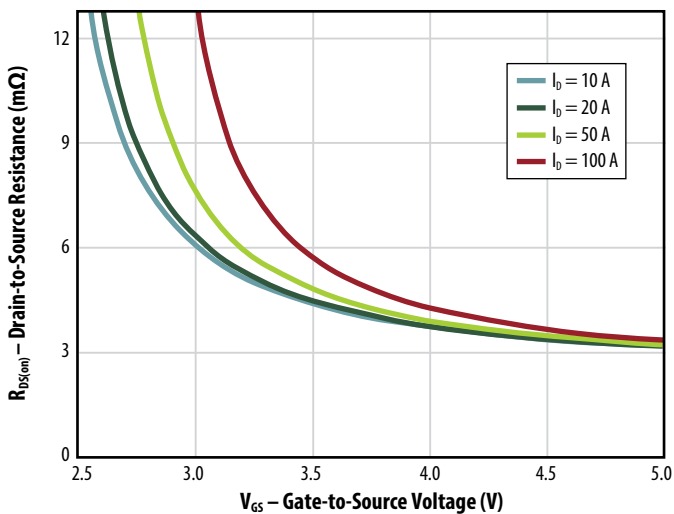


Figure 4:  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Temperatures

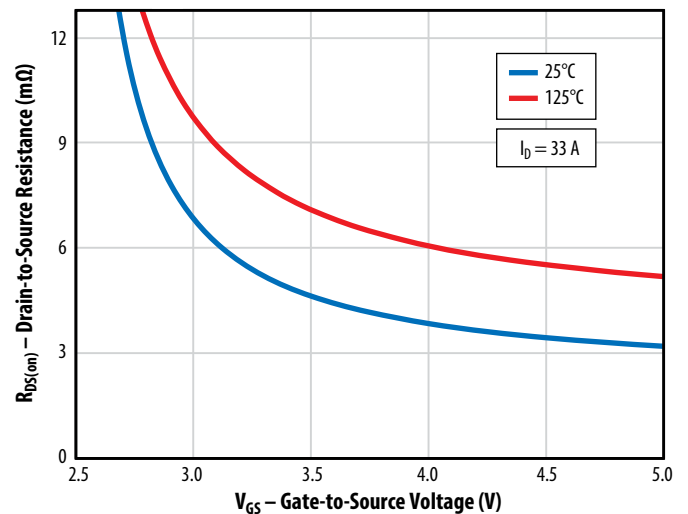


Figure 5a: Capacitance (Linear Scale)

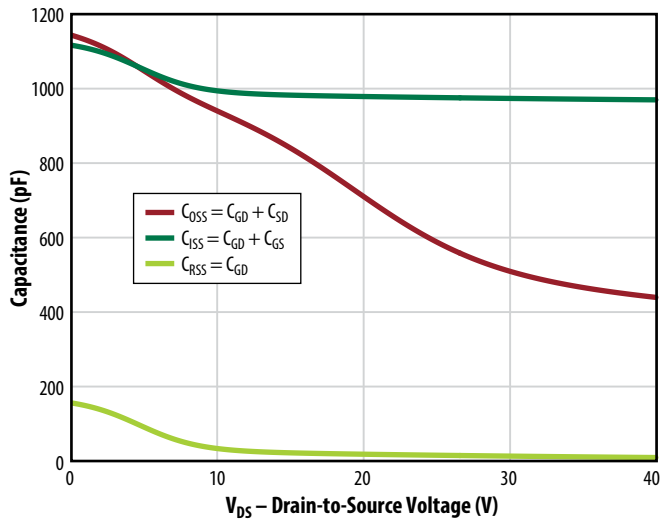


Figure 5b: Capacitance (Log Scale)

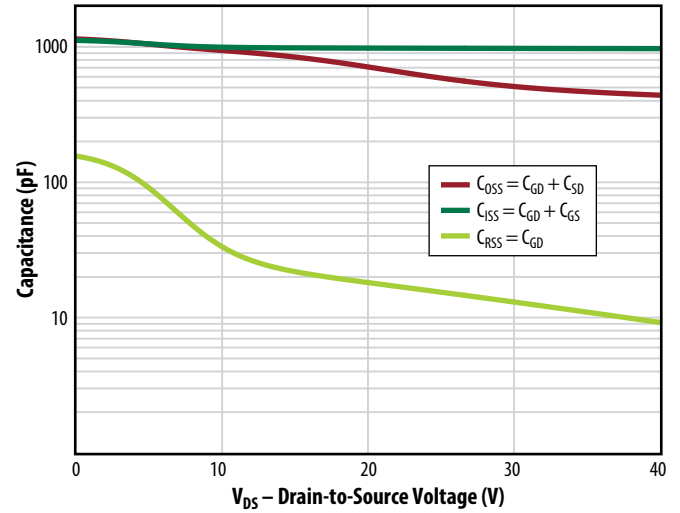


Figure 6: Gate Charge

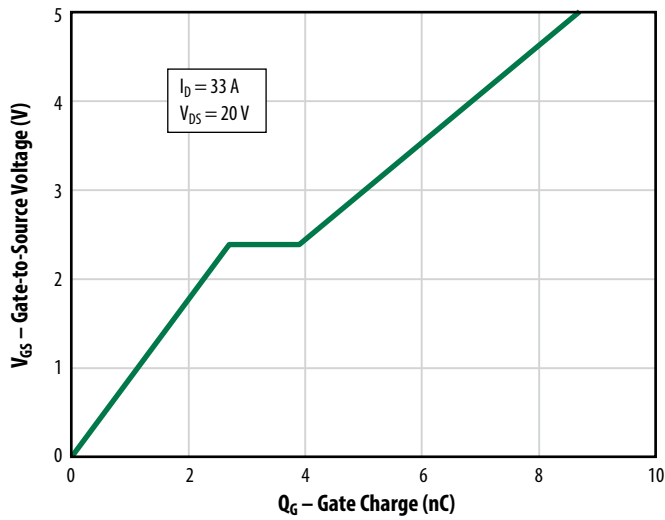


Figure 7: Reverse Drain-Source Characteristics

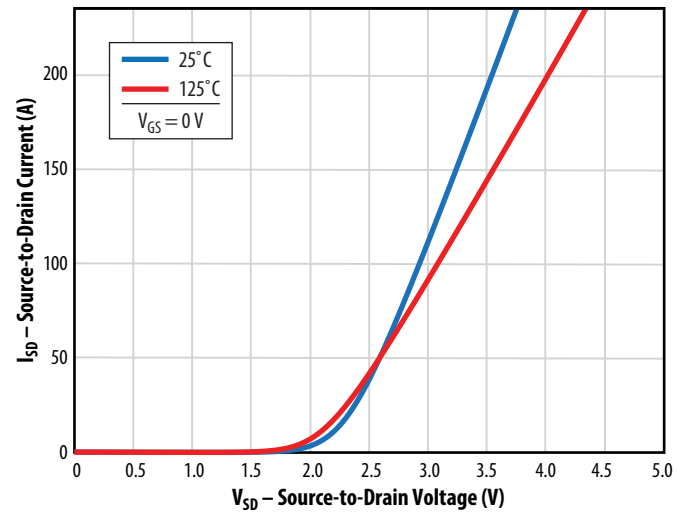


Figure 8: Normalized On-State Resistance vs. Temperature

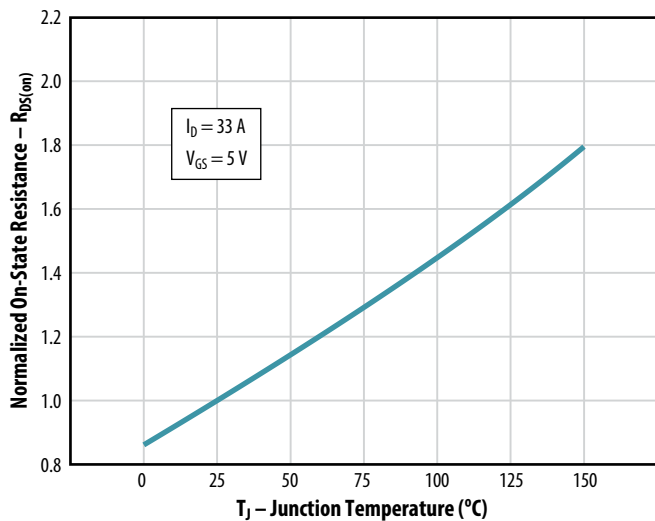
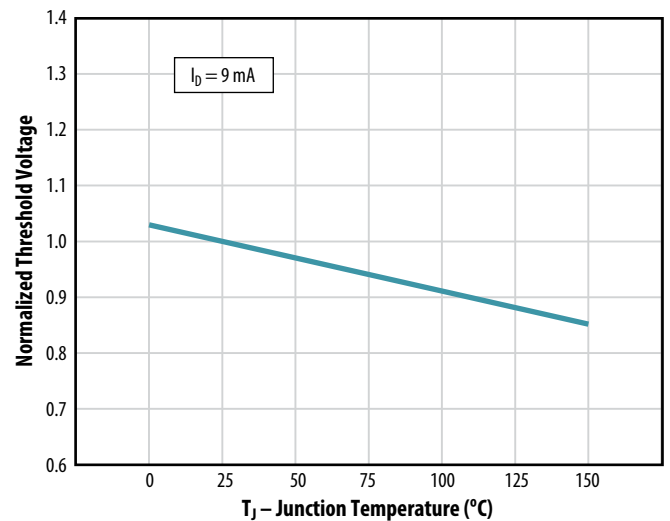


Figure 9: Normalized Threshold Voltage vs. Temperature



All measurements were done with substrate shorted to source.

Figure 10: Gate Leakage Current

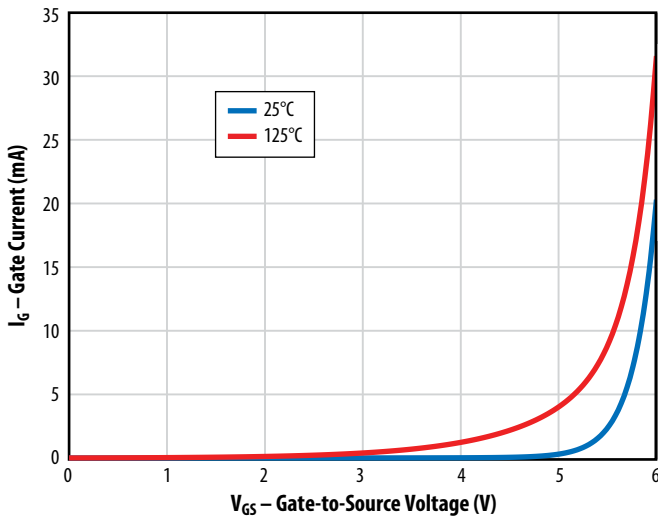


Figure 11: Safe Operating Area

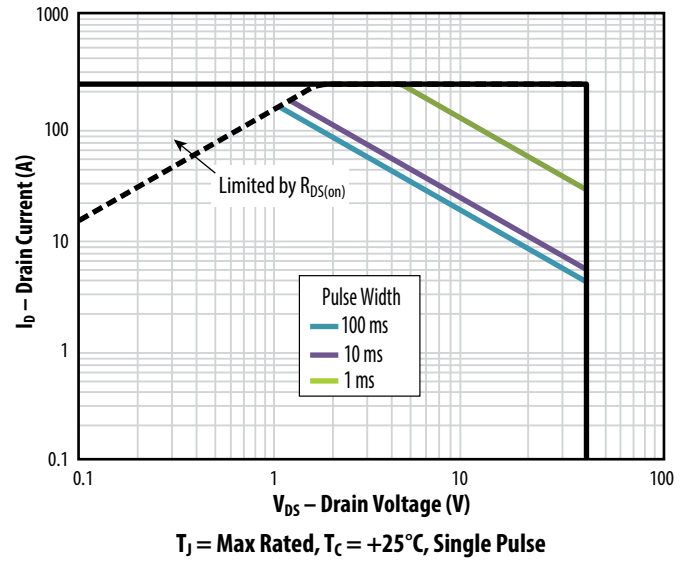
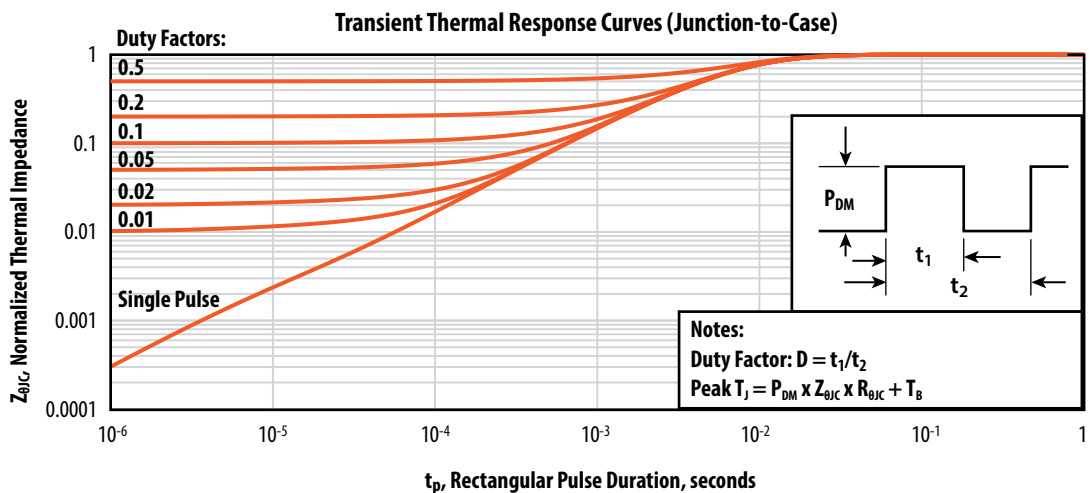
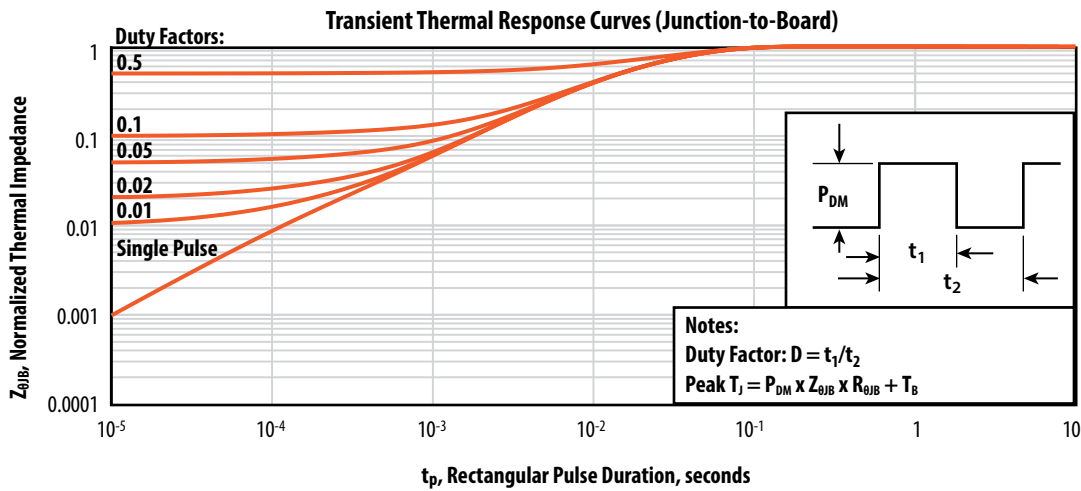
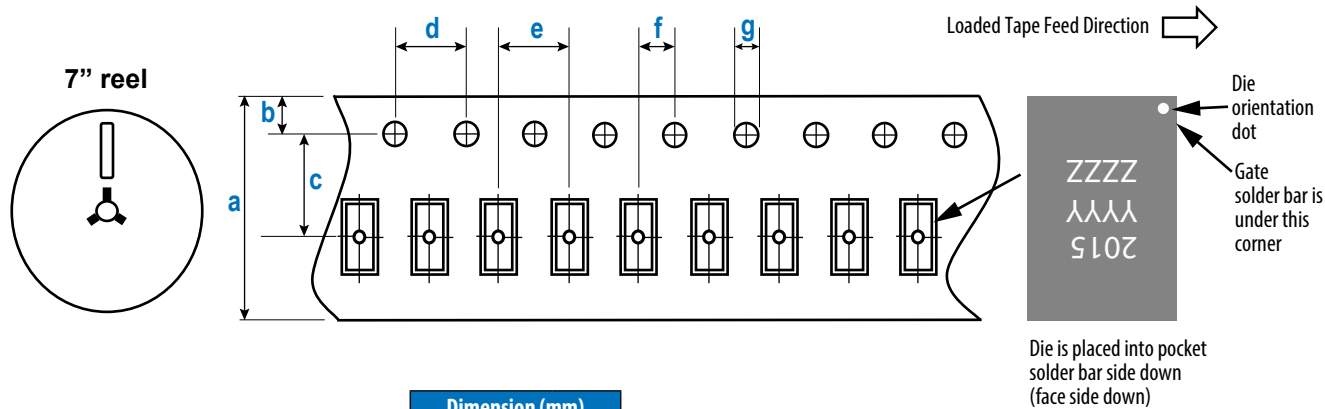


Figure 12: Transient Thermal Response Curves



**TAPE AND REEL CONFIGURATION**

4 mm pitch, 12 mm wide tape on 7" reel

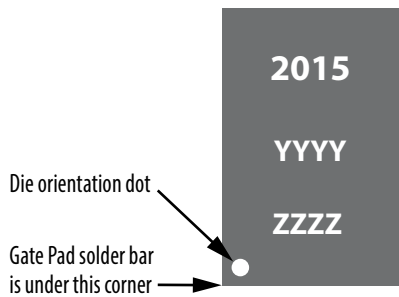


EPC2015 (Note 1)	Dimension (mm)		
	Target	MIN	MAX
<b>a</b>	12.00	11.90	12.30
<b>b</b>	1.75	1.65	1.85
<b>c</b> (Note 2)	5.50	5.45	5.55
<b>d</b>	4.00	3.90	4.10
<b>e</b>	4.00	3.90	4.10
<b>f</b> (Note 2)	2.00	1.95	2.05
<b>g</b>	1.50	1.50	1.60

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.

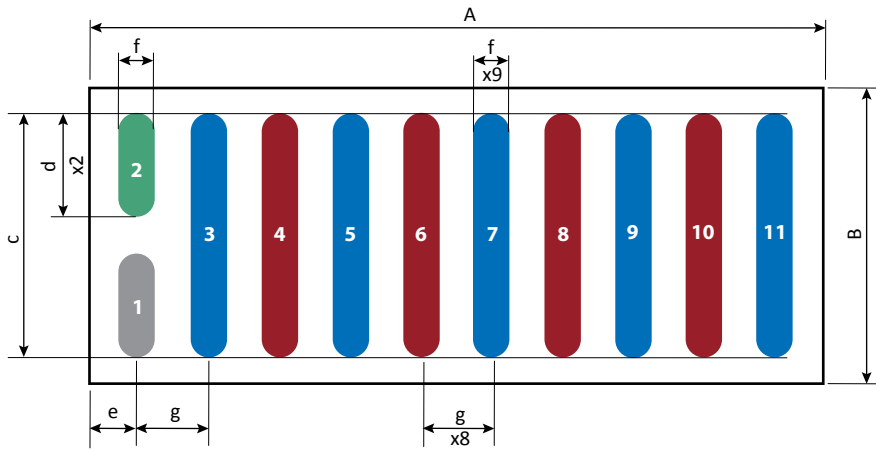
Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

**DIE MARKINGS**



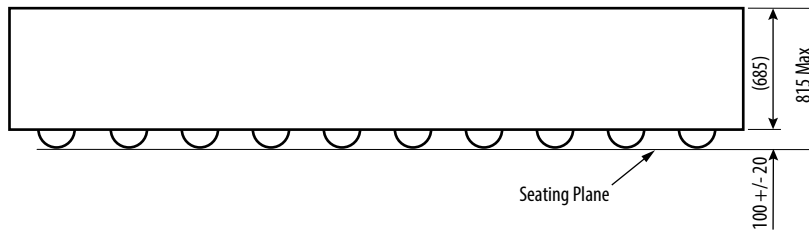
Part Number	Laser Markings		
	Part # Marking Line 1	Lot_ Date Code Marking Line 2	Lot_ Date Code Marking Line 3
EPC2015C	2015	YYYY	ZZZZ

**DIE OUTLINE**  
Solder Bar View



DIM	MICROMETERS		
	MIN	Nominal	MAX
A	4075	4105	4135
B	1602	1635	1662
c	1379	1382	1385
d	577	580	583
e	235	250	265
f	195	200	205
g	400	400	400

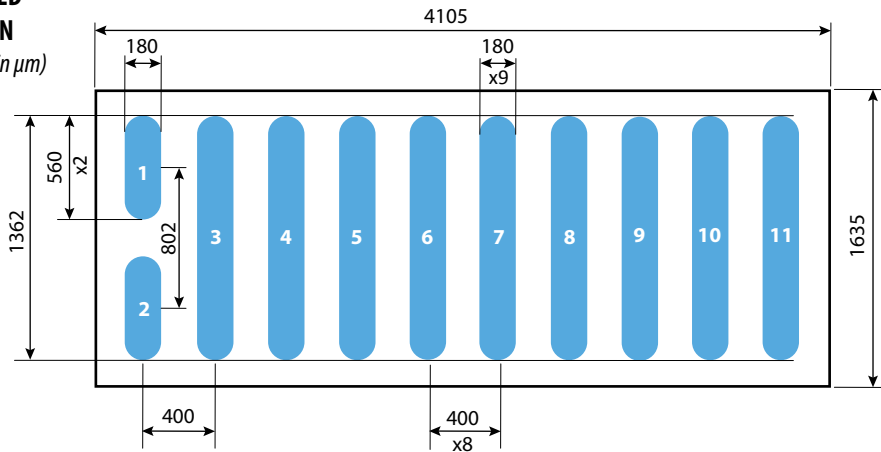
Side View



Pad no. 1 is Gate;  
 Pads no. 3, 5, 7, 9, 11 are Drain;  
 Pads no. 4, 6, 8, 10 are Source;  
 Pad no. 2 is Substrate.\*

\*Substrate pin should be connected to Source

**RECOMMENDED LAND PATTERN**  
(measurements in  $\mu\text{m}$ )

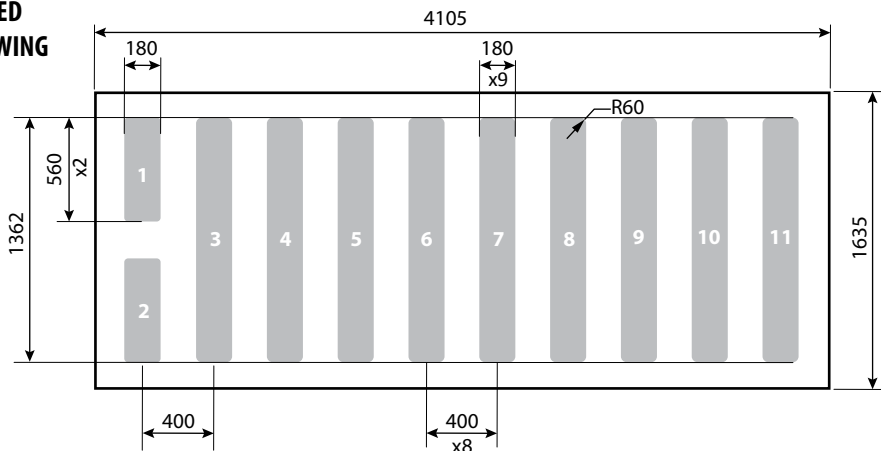


The land pattern is solder mask defined.

Pad no. 1 is Gate;  
 Pads no. 3, 5, 7, 9, 11 are Drain;  
 Pads no. 4, 6, 8, 10 are Source;  
 Pad no. 2 is Substrate.\*

\*Substrate pin should be connected to Source

**RECOMMENDED STENCIL DRAWING**  
(units in  $\mu\text{m}$ )



Recommended stencil should be 4 mil (100  $\mu\text{m}$ ) thick, must be laser cut, opening per drawing. The corner has a radius of R60.

Intended for use with SAC305 Type 3 solder, reference 88.5% metals content.

Additional assembly resources available at <http://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx>

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